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119 Cited Documents from "Zhang, Zhengxuan"

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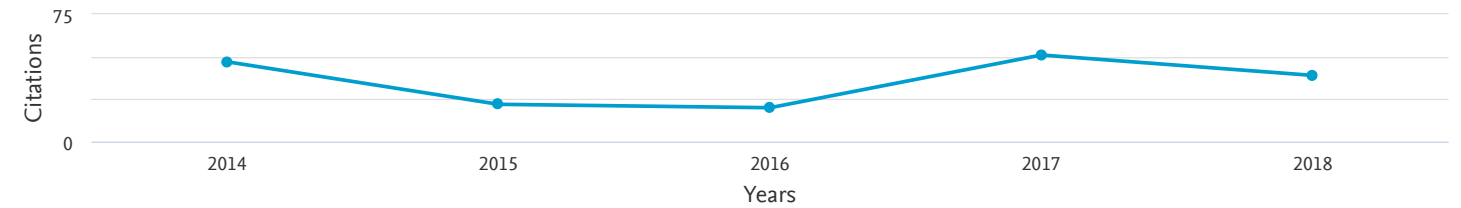
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		Total	142	47	22	20	51	39	179	0	321
<input type="checkbox"/> 1	Total-ionizing-dose induced coupling effect in the 130-nm PD...	2014			1	2	9	1	13		13
<input type="checkbox"/> 2	Bias dependence of TID radiation responses of 0.13 μm partia...	2013	3	2	2	1	2	3	10		13
<input type="checkbox"/> 3	Comprehensive study on the total dose effects in a 180-nm CM...	2011	4	2	2	1	2	2	9		13
<input type="checkbox"/> 4	Improvement of total-dose irradiation hardness of silicon-on...	2006	7		2	1	1	2	6		13
<input type="checkbox"/> 5	A new structure of SOI MOSFET for reducing self-heating effe...	2004	7				3	1	4		11
<input type="checkbox"/> 6	Bias dependence of a deep submicron NMOSFET response to tota...	2011	4	4		1	1		6		10
<input type="checkbox"/> 7	Improving total dose tolerance of buried oxides in SOI wafer...	2014			1	3	2	3	9		9
<input type="checkbox"/> 8	Total ionizing dose enhanced DIBL effect for deep submicron ...	2011	3	1	1		4		6		9
<input type="checkbox"/> 9	Effect of nanoclusters induced by Si implantation on total d...	2008	7	1			1		2		9
<input type="checkbox"/> 10	The influence of channel length on total ionizing dose effec...	2012	5	1			1		2		7
<input type="checkbox"/> 11	Simple method for extracting effective sheet charge density ...	2011	3	2				2	4		7
<input type="checkbox"/> 12	Research on metastable electron traps in the modified SOI ma...	2008	3			1		3	4		7
<input type="checkbox"/> 13	Effects of Si ion implantation on the total-dose radiation p...	2007	6		1				1		7
<input type="checkbox"/> 14	A new structure of silicon-on-insulator metal-oxide-semicond...	2003	6	1					1		7
<input type="checkbox"/> 15	Influence of Si nanocrystal embedded in BOX on radiation and...	2012		1		2		3	6		6
<input type="checkbox"/> 16	Impact of substrate bias on radiation-induced edge effects i...	2011	3	1			2		3		6
<input type="checkbox"/> 17	Enhanced total ionizing dose susceptibility in narrow channe...	2011	3	1			1	1	3		6
<input type="checkbox"/> 18	Influence of nitrogen element on total-dose radiation respon...	2007	6						0		6
<input type="checkbox"/> 19	A study on the total-dose response for modified silicon-on-i...	2006	4		1	1			2		6
<input type="checkbox"/> 20	Total ionizing dose effect in 0.2 μm PDSOI NMOSFETs with sha...	2014			1	1	3		5		5

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